



#### **FEATURES**

- Controlled Baseline
  - One Assembly/Test Site, One Fabrication Site
- Enhanced Diminishing Manufacturing Sources (DMS) Support
- Enhanced Product-Change Notification
- Qualification Pedigree (1)
- Member of the Texas Instruments Widebus™
   Family
- Operates From 1.65 V to 3.6 V
- Inputs Accept Voltages to 5.5 V
- Max t<sub>nd</sub> of 4.1 ns at 3.3 V
- Typical V<sub>OLP</sub> (Output Ground Bounce)
   <0.8 V at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C
- Typical V<sub>OHV</sub> (Output V<sub>OH</sub> Undershoot)
   >2 V at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C
- I<sub>off</sub> Supports Partial-Power-Down Mode Operation
- Supports Mixed-Mode Signal Operation On All Ports (5-V Input/Output Voltage With 3.3-V V<sub>CC</sub>)
- Latch-Up Performance Exceeds 250 mA Per JFSD 17
- ESD Protection Exceeds JESD 22
  - 2000-V Human-Body Model (A114-A)
  - 1000-V Charged-Device Model (C101)
- (1) Component qualification in accordance with JEDEC and industry standards to ensure reliable operation over an extended temperature range. This includes, but is not limited to, Highly Accelerated Stress Test (HAST) or biased 85/85, temperature cycle, autoclave or unbiased HAST, electromigration, bond intermetallic life, and mold compound life. Such qualification testing should not be viewed as justifying use of this component beyond specified performance and environmental limits.

# DGG PACKAGE (TOP VIEW)

1 <del>OE</del>		1	$\cup$	48	þ	2 <del>OE</del>
1Y1		2		47	þ	1A1
1Y2		3		46	þ	1A2
GND		4		45	þ	GND
1Y3		5		44	þ	1A3
1Y4		6		43	þ	1A4
$V_{CC}$		7		42	1	$V_{CC}$
2Y1		8		41	1	2A1
2Y2		9		40	1	2A2
GND		10		39	1	GND
2Y3		11		38		2A3
2Y4		12		37	þ	2A4
3Y1		13		36	þ	3A1
3Y2		14		35	þ	3A2
GND		15		34	þ	GND
3Y3		16		33	þ	3A3
3Y4		17		32	þ	3A4
$V_{CC}$		18		31	þ	$V_{CC}$
4Y1		19		30	1	4A1
4Y2		20		29	1	4A2
GND		21		28	1	GND
4Y3	Ц	22		27	þ	4A3
4Y4		23		-	ч	4A4
4 <del>OE</del>		24		25	þ	3 <del>OE</del>
	ı				•	

#### **DESCRIPTION/ORDERING INFORMATION**

This 16-bit buffer/driver is designed for 1.65-V to 3.6-V  $V_{CC}$  operation.

The SN74LVC16244A is designed specifically to improve the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters.

#### ORDERING INFORMATION

T <sub>A</sub>	PACKAGE <sup>(1)</sup>		ORDERABLE PART NUMBER	TOP-SIDE MARKING
-40°C to 85°C	TSSOP - DGG	Tape and reel	CLVC16244AIDGGREP	C16244AEP

(1) Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.



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## **DESCRIPTION/ORDERING INFORMATION (CONTINUED)**

The device can be used as four 4-bit buffers, two 8-bit buffers, or one 16-bit buffer. It provides true outputs and symmetrical active-low output-enable  $(\overline{OE})$  inputs.

Inputs can be driven from either 3.3-V or 5-V devices. This feature allows the use of this device as a translator in a mixed 3.3-V/5-V system environment.

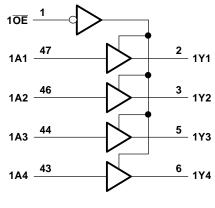
This device is fully specified for partial-power-down applications using  $I_{\text{off}}$ . The  $I_{\text{off}}$  circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.

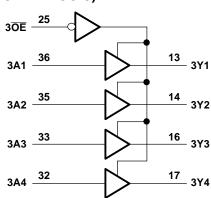
To ensure the high-impedance state during power up or power down,  $\overline{OE}$  should be tied to  $V_{CC}$  through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

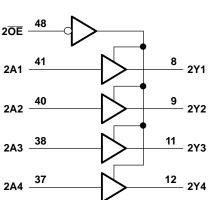
# FUNCTION TABLE (EACH 4-BIT BUFFER)

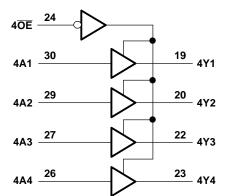
INPU	OUTPUT	
ŌĒ	Α	Y
L	Н	Н
L	L	L
Н	Χ	Z

#### **LOGIC DIAGRAM (POSITIVE LOGIC)**













## Absolute Maximum Ratings<sup>(1)</sup>

over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT
$V_{CC}$	Supply voltage range		-0.5	6.5	V
VI	Input voltage range <sup>(2)</sup>		-0.5	6.5	V
Vo	Voltage range applied to any output in the hi	gh-impedance or power-off state <sup>(2)</sup>	-0.5	6.5	V
Vo	Voltage range applied to any output in the hi	gh or low state <sup>(2)(3)</sup>	-0.5	V <sub>CC</sub> + 0.5	V
I <sub>IK</sub>	Input clamp current	V <sub>I</sub> < 0		-50	mA
I <sub>OK</sub>	Output clamp current	V <sub>O</sub> < 0		<b>-</b> 50	mA
Io	Continuous output current			±50	mA
	Continuous current through each V <sub>CC</sub> or GN	D		±100	mA
$\theta_{JA}$	Package thermal impedance (4)			70	°C/W
T <sub>stg</sub>	Storage temperature range		-65	150	°C

<sup>(1)</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- (2) The input and output negative-voltage ratings may be exceeded if the input and output current ratings are observed.
- (3) The value of V<sub>CC</sub> is provided in the recommended operating conditions table.
- (4) The package thermal impedance is calculated in accordance with JESD 51-7.

## Recommended Operating Conditions<sup>(1)</sup>

			MIN	MAX	UNIT		
.,	Complementary	Operating	1.65	3.6	V		
$V_{CC}$	Supply voltage	Data retention only	1.5		V		
		V <sub>CC</sub> = 1.65 V to 1.95 V	0.65 × V <sub>CC</sub>				
$V_{IH}$	High-level input voltage				V		
		V <sub>CC</sub> = 2.7 V to 3.6 V	2				
		V <sub>CC</sub> = 1.65 V to 1.95 V		$0.35 \times V_{CC}$			
$V_{IL}$	Low-level input voltage	V <sub>CC</sub> = 2.3 V to 2.7 V		0.7	V		
		V <sub>CC</sub> = 2.7 V to 3.6 V					
VI	Input voltage	·	0	5.5	V		
	Outside as lie as	High or low state	0	$V_{CC}$	V		
Vo	Output voltage	3-state	0	5.5			
		V <sub>CC</sub> = 1.65 V		-4			
	Lligh level output ourrent	V <sub>CC</sub> = 2.3 V		-8	A		
I <sub>OH</sub>	High-level output current	V <sub>CC</sub> = 2.7 V		-12	mA		
		V <sub>CC</sub> = 3 V		-24			
		V <sub>CC</sub> = 1.65 V		4			
	Lour lovel output ourrent	V <sub>CC</sub> = 2.3 V		8	A		
I <sub>OL</sub>	Low-level output current	V <sub>CC</sub> = 2.7 V		12	mA		
		V <sub>CC</sub> = 3 V		24			
Δt/Δν	Input transition rise or fall rate			10	ns/V		
T <sub>A</sub>	Operating free-air temperature		-40	85	°C		

<sup>(1)</sup> All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



## **Electrical Characteristics**

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST C	ONDITIONS	V <sub>cc</sub>	MIN T	YP <sup>(1)</sup> MAX	UNIT	
	$I_{OH} = -100 \mu A$		1.65 V to 3.6 V	V <sub>CC</sub> - 0.2			
	$I_{OH} = -4 \text{ mA}$		1.65 V	1.2			
\ <u>'</u>	$I_{OH} = -8 \text{ mA}$		2.3 V	1.7		V	
V <sub>OH</sub>	L – 12 mΛ		2.7 V	2.2		V	
	I <sub>OH</sub> = −12 mA		3 V	2.4			
	$I_{OH} = -24 \text{ mA}$		3 V	2.2			
	I <sub>OL</sub> = 100 μA		1.65 V to 3.6 V		0.2		
	I <sub>OL</sub> = 4 mA		1.65 V		0.45	5	
V <sub>OL</sub>	I <sub>OL</sub> = 8 mA		2.3 V		0.7	V	
	I <sub>OL</sub> = 12 mA		2.7 V		0.4		
	$I_{OL} = 24 \text{ mA}$		3 V		0.55		
I <sub>I</sub>	V <sub>I</sub> = 0 to 5.5 V		3.6 V		±5	μΑ	
I <sub>off</sub>	$V_I$ or $V_O = 5.5 \text{ V}$		0		±10	μΑ	
I <sub>OZ</sub>	$V_0 = 0 \text{ to } 5.5 \text{ V}$		3.6 V		±10	μΑ	
1	$V_I = V_{CC}$ or GND	1 - 0	3.6 V		20		
I <sub>CC</sub>	$3.6 \text{ V} \le V_I \le 5.5 \text{ V}^{(2)}$	$I_0 = 0$	3.0 V	20		μΑ	
Δl <sub>CC</sub>	One input at V <sub>CC</sub> – 0.6 V,	Other inputs at V <sub>CC</sub> or GND	2.7 V to 3.6 V		500	μΑ	
C <sub>i</sub>	$V_I = V_{CC}$ or GND		3.3 V		5.5	pF	
Co	V <sub>O</sub> = V <sub>CC</sub> or GND		3.3 V		6	pF	

<sup>(1)</sup> All typical values are at  $V_{CC}$  = 3.3 V,  $T_A$  = 25°C. (2) This applies in the disabled state only.

## **Switching Characteristics**

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub> = ± 0.1		V <sub>CC</sub> = 2 ± 0.2	2.5 V 2 V	V <sub>CC</sub> =	2.7 V	V <sub>CC</sub> = 3 ± 0.3	3.3 V 3 V	UNIT
	(INPUT)	(001701)	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t <sub>pd</sub>	Α	Υ	1.5	6.6	1	3.9	1	4.7	1.1	4.1	ns
t <sub>en</sub>	ŌĒ	Y	1.5	7.5	1	4.7	1	5.8	1	4.6	ns
t <sub>dis</sub>	ŌĒ	Y	1.5	10.3	1	5.3	1	6.2	1.8	5.8	ns
t <sub>sk(o)</sub>										1	ns

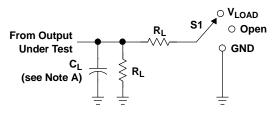
## **Operating Characteristics**

 $T_A = 25^{\circ}C$ 

	PARAMETER		TEST CONDITIONS	V <sub>CC</sub> = 1.8 V TYP	V <sub>CC</sub> = 2.5 V TYP	V <sub>CC</sub> = 3.3 V TYP	UNIT
_	Power dissipation capacitance	Outputs enabled	f = 10 MHz	33	35	39	pF
$C_{pd}$	per buffer/driver	Outputs disabled	I = IO WINZ	2	3	4	рг



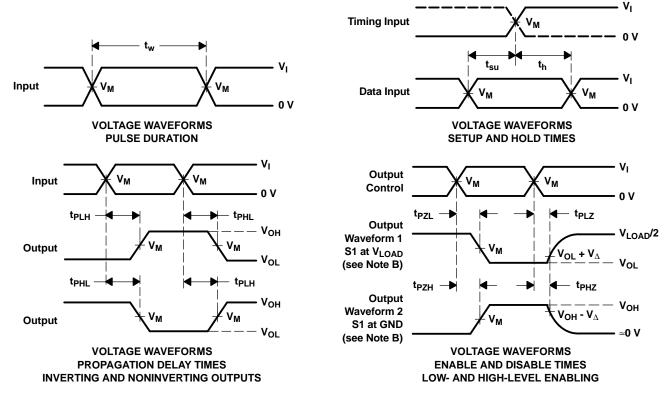
#### PARAMETER MEASUREMENT INFORMATION



TEST	S1
t <sub>PLH</sub> /t <sub>PHL</sub>	Open
t <sub>PLZ</sub> /t <sub>PZL</sub>	V <sub>LOAD</sub>
t <sub>PHZ</sub> /t <sub>PZH</sub>	GND

**LOAD CIRCUIT** 

.,	INI	PUTS	.,	.,		_	
V <sub>CC</sub>	VI	t <sub>r</sub> /t <sub>f</sub>	V <sub>M</sub>	V <sub>LOAD</sub>	CL	R <sub>L</sub>	$oldsymbol{V}_\Delta$
1.8 V ± 0.15 V	V <sub>CC</sub>	≤2 ns	V <sub>CC</sub> /2	2×V <sub>CC</sub>	30 pF	<b>1 k</b> Ω	0.15 V
2.5 V $\pm$ 0.2 V	V <sub>CC</sub>	≤2 ns	V <sub>CC</sub> /2	2×V <sub>CC</sub>	30 pF	500 Ω	0.15 V
2.7 V	2.7 V	≤2.5 ns	1.5 V	6 V	50 pF	500 Ω	0.3 V
3.3 V $\pm$ 0.3 V	2.7 V	≤2.5 ns	1.5 V	6 V	50 pF	500 Ω	0.3 V



NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz, Z<sub>O</sub> = 50  $\Omega$ .
- D. The outputs are measured one at a time, with one transition per measurement.
- E.  $t_{PLZ}$  and  $t_{PHZ}$  are the same as  $t_{dis}$ .
- F.  $\,t_{PZL}$  and  $t_{PZH}$  are the same as  $t_{en}.$
- G.  $t_{PLH}$  and  $t_{PHL}$  are the same as  $t_{pd}$ .
- H. All parameters and waveforms are not applicable to all devices.

Figure 1. Load Circuit and Voltage Waveforms



## PACKAGE OPTION ADDENDUM

10-Dec-2020

#### PACKAGING INFORMATION

www.ti.com

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
CLVC16244AIDGGREP	ACTIVE	TSSOP	DGG	48	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	C16244AEP	Samples
V62/04724-01XE	ACTIVE	TSSOP	DGG	48	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	C16244AEP	Samples

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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## **PACKAGE OPTION ADDENDUM**

10-Dec-2020

#### OTHER QUALIFIED VERSIONS OF SN74LVC16244A-EP:

● Catalog: SN74LVC16244A

• Automotive: SN74LVC16244A-Q1

NOTE: Qualified Version Definitions:

• Catalog - TI's standard catalog product

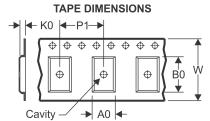
• Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects

## **PACKAGE MATERIALS INFORMATION**

www.ti.com 11-Mar-2017

## TAPE AND REEL INFORMATION





		Dimension designed to accommodate the component width
		Dimension designed to accommodate the component length
		Dimension designed to accommodate the component thickness
	W	Overall width of the carrier tape
ľ	P1	Pitch between successive cavity centers

## QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing			Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CLVC16244AIDGGREP	TSSOP	DGG	48	2000	330.0	24.4	8.6	13.0	1.8	12.0	24.0	Q1

www.ti.com 11-Mar-2017



#### \*All dimensions are nominal

Device Package Type		Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
CLVC16244AIDGGREP	TSSOP	DGG	48	2000	367.0	367.0	45.0	



SMALL OUTLINE PACKAGE



### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
  4. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 5. Publication IPC-7351 may have alternate designs.
- 6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 8. Board assembly site may have different recommendations for stencil design.



## DGG (R-PDSO-G\*\*)

## PLASTIC SMALL-OUTLINE PACKAGE

#### **48 PINS SHOWN**



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold protrusion not to exceed 0,15.

D. Falls within JEDEC MO-153

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